

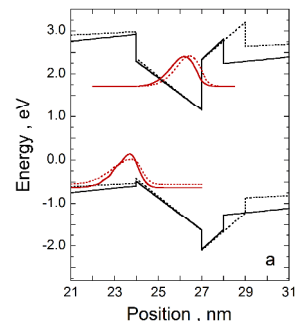
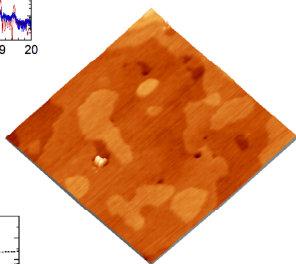
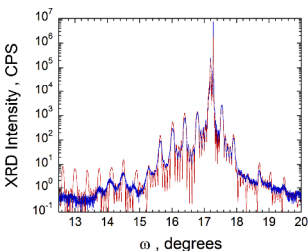
# Increased Indium Incorporation and Efficiency in InGaN Quantum Wells Emitting at 530-590 nm with AlGaN Interlayers

**Daniel D. Koleske<sup>\*</sup>, Arthur J. Fischer, B. N. Bryant and Jonathan J. Wierer, Jr<sup>‡</sup>.**

*Sandia National Laboratories, Albuquerque, NM, 87185, USA*

[\\*ddkoles@sandia.gov](mailto:*ddkoles@sandia.gov)

<sup>‡</sup> *currently at Lehigh University, Dept. Electrical and Computer Engineering.*



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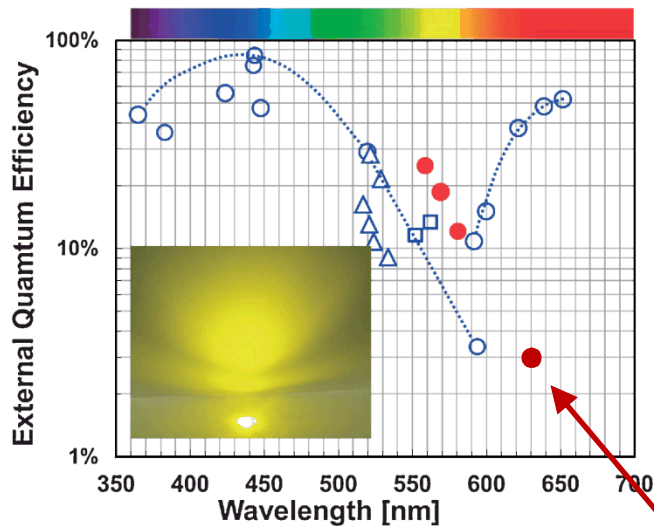
The 17<sup>th</sup> U.S. Biennial Workshop on Organometallic Vapor Phase Epitaxy (OMVPE-17)  
August 2<sup>nd</sup>-7<sup>th</sup>, 2015, Big Sky, Montana, USA



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# Bright yellow and red LEDs from Toshiba

Higher EQE at green-gap wavelengths  
Saito – Appl. Phys. Exp. 6 (2013) 111004

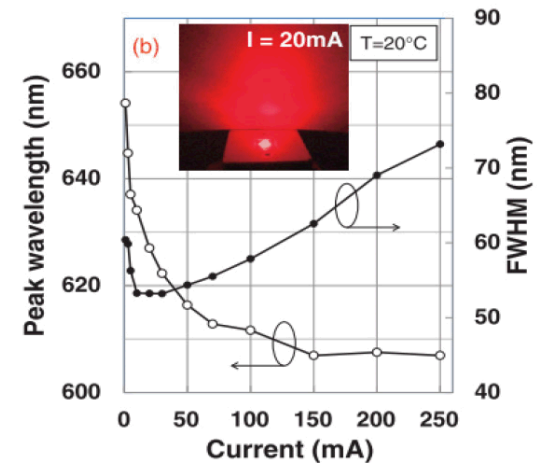
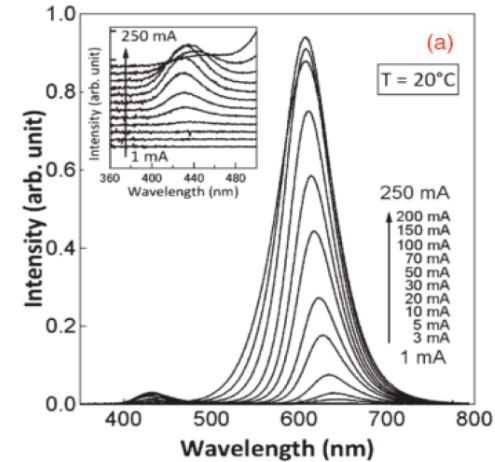


InGaN barrier ~1 %	10 nm
AlGaIn IL ~40 %	1 nm
InGaN QW ~26% – 576 nm	3 nm
InGaN barrier ~1 %	10 nm

Is capping the QW with AlGaIn IL the key?

Hwang – Appl. Phys. Exp. 7 (2014) 071003.

35%  
InGaN  
QWs?



Achieved 1.1 mW @ 20 mA and EQE of 2.9 %,  
629 nm @ 20 mA and 608 nm @ 200 mA

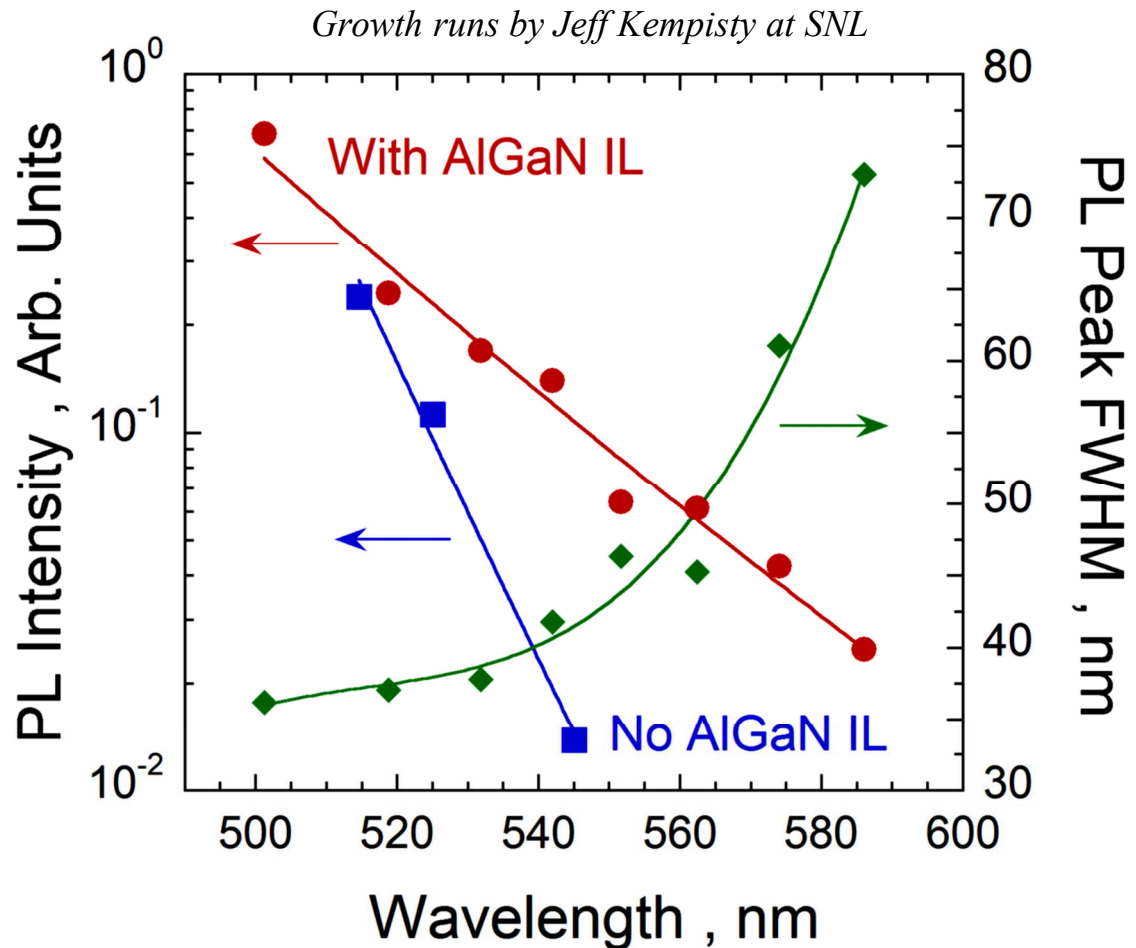
# How does the AlGaN interlayer (IL) work?

*More details in D.D. Koleske et al., Journal of Crystal Growth 415 (2015) 57-64*

- What are the exact growth conditions?
  - AlGaN IL growth?, special conditions?
  - Use GaN barriers instead of 1 % InGaN barriers. Optimal temperature?
  - Growth sequence? When to ramp? When to start GaN barrier growth?
  - Can the structures be verified using XRD?
- Influence of AlGaN IL on the QW emission properties.
  - Can more indium be put in the InGaN QW?
    - Is it possible to go above the ~20% coherency strain limit for InGaN on GaN.
    - Does the InGaN QW strain relax?
    - Can the AlGaN IL prevent InGaN QW decomposition?
- AlGaN IL also influences the polarization fields
  - PL wavelength?, and PL intensity?

# Yes it works – to some degree

- OMVPE Equipment
  - Veeco D125 - short jar
  - Active region @ 300 torr
  - 700 RPM
- InGaN growth
  - TMIn ~100  $\mu\text{moles/min}$ , temperature controls indium
  - 15 SLM  $\text{NH}_3$ , 10 SLM  $\text{N}_2$
- QW growth
  - $T = 690$  to  $730^\circ\text{C}$
  - QWs on InGaN underlayers\*
  - Gray QWs below  $730^\circ\text{C}$  without AlGaN ILs
- AlGaN interlayer (IL)
  - Same temperature as QWs
- GaN barriers
  - Grown at  $800$  to  $900^\circ\text{C}$

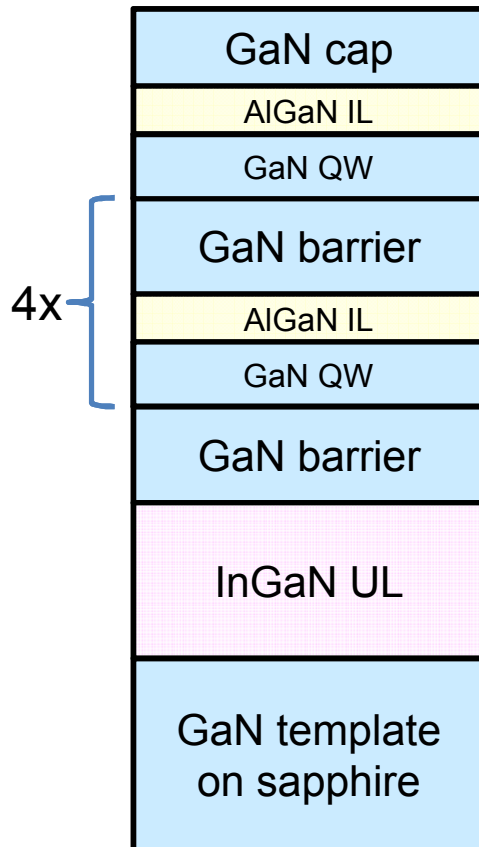


\*For UL reference see Armstrong, JAP 117, 134501 (2015).

10x improvement in PL intensity with IL, helps only for wavelengths > 520 nm

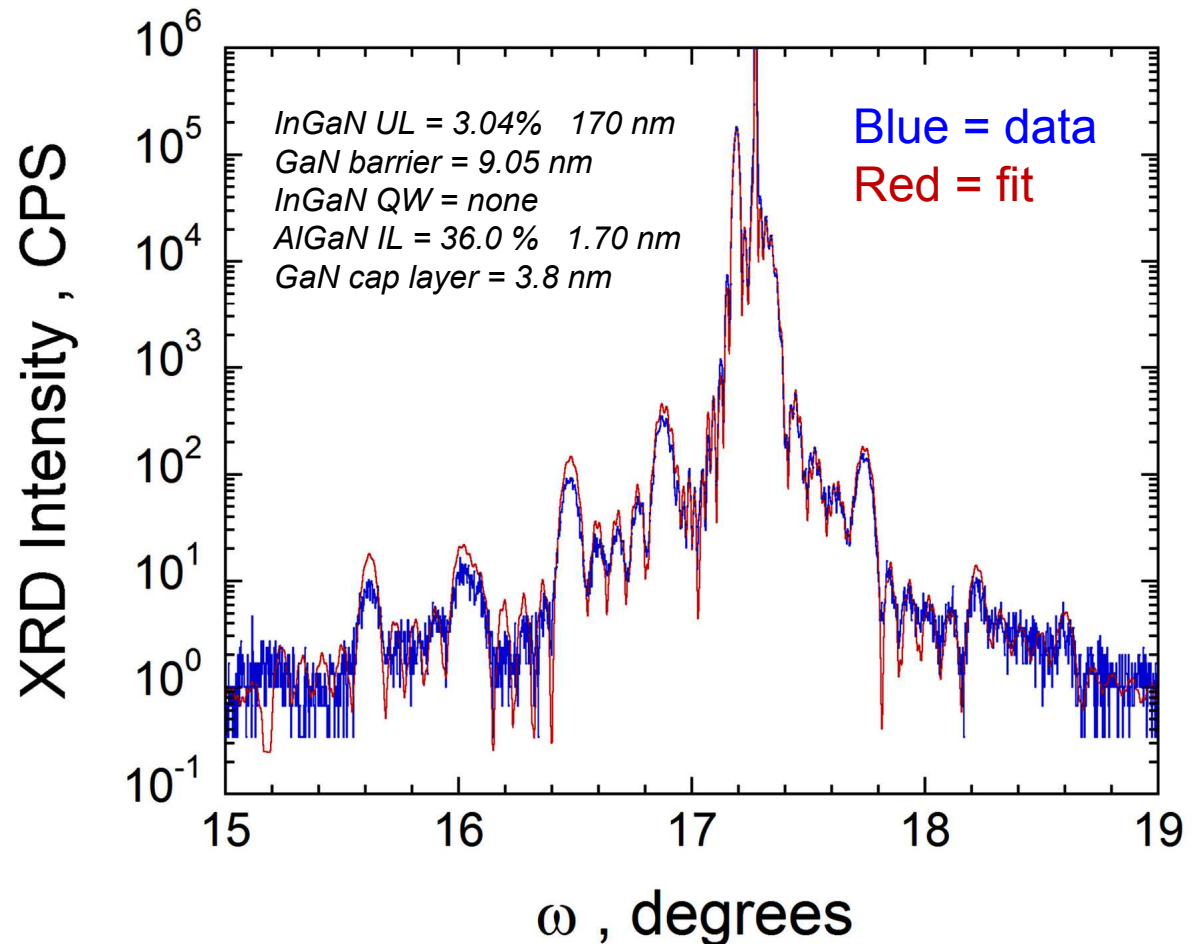
# Calibration of the AlGaIn layer using XRD

Grow InGaIn QW structure  
without indium



Target gas phase Al/(Al+Ga) = 0.40

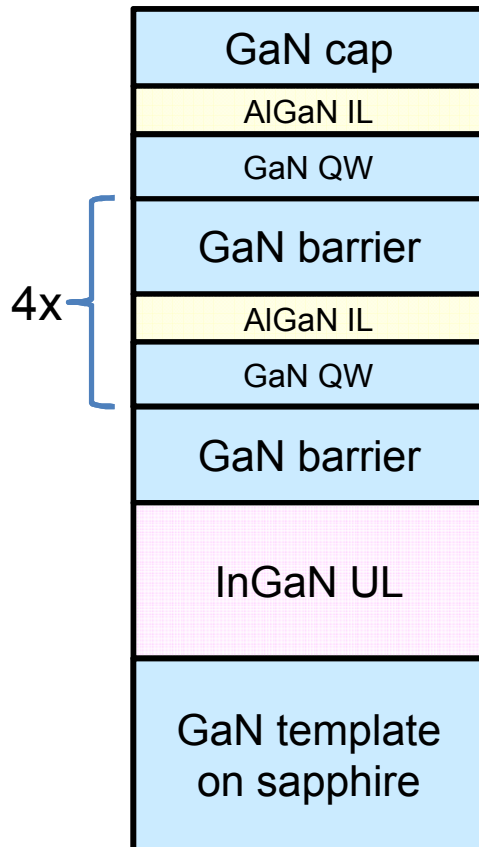
Get solid phase Al/(Al+Ga) = 0.36, 1.7 nm



*XRD fit uses Panalytical's Expert 4.0*

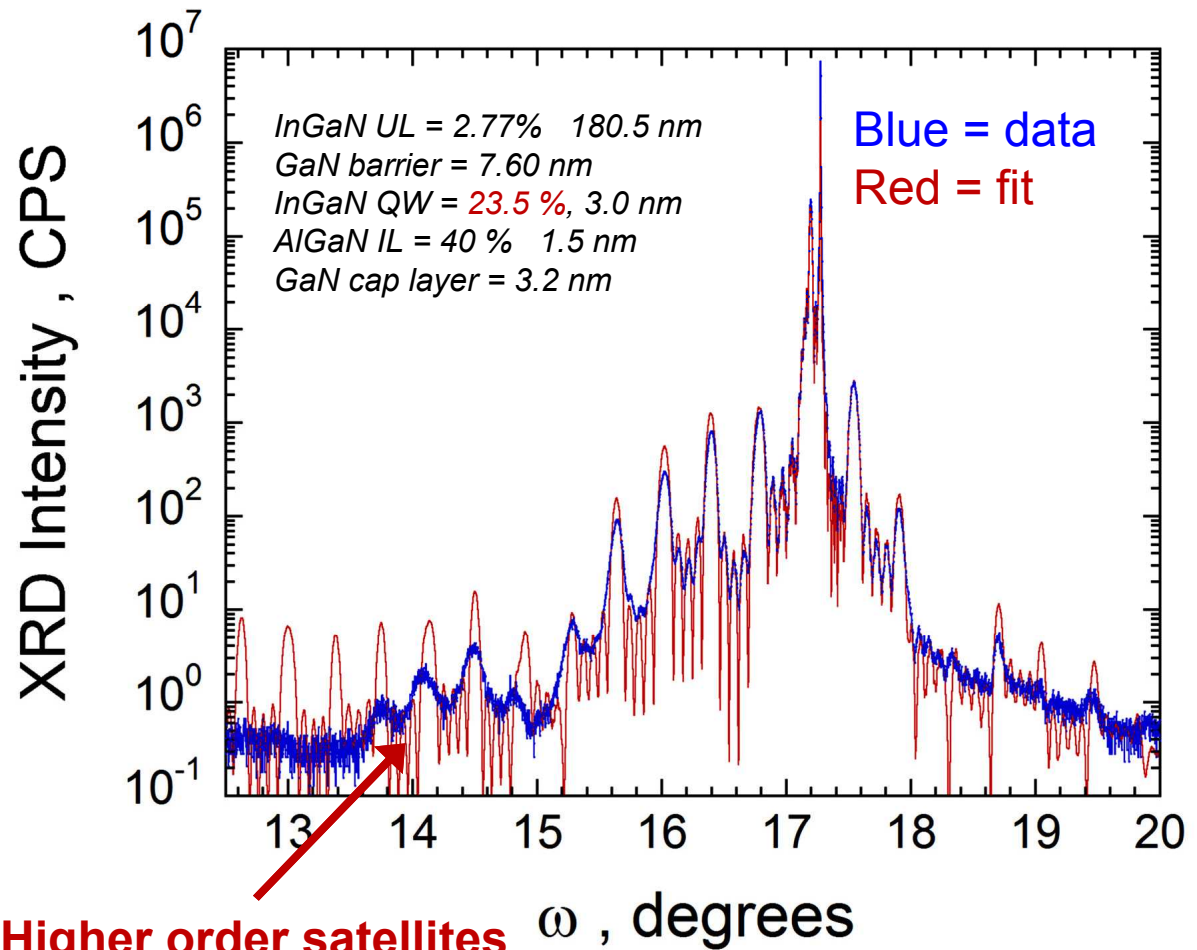
# XRD fit of the full structure

Put indium back into the  
QW structure



Adjust aluminum flows to get 40 % AlGaIn

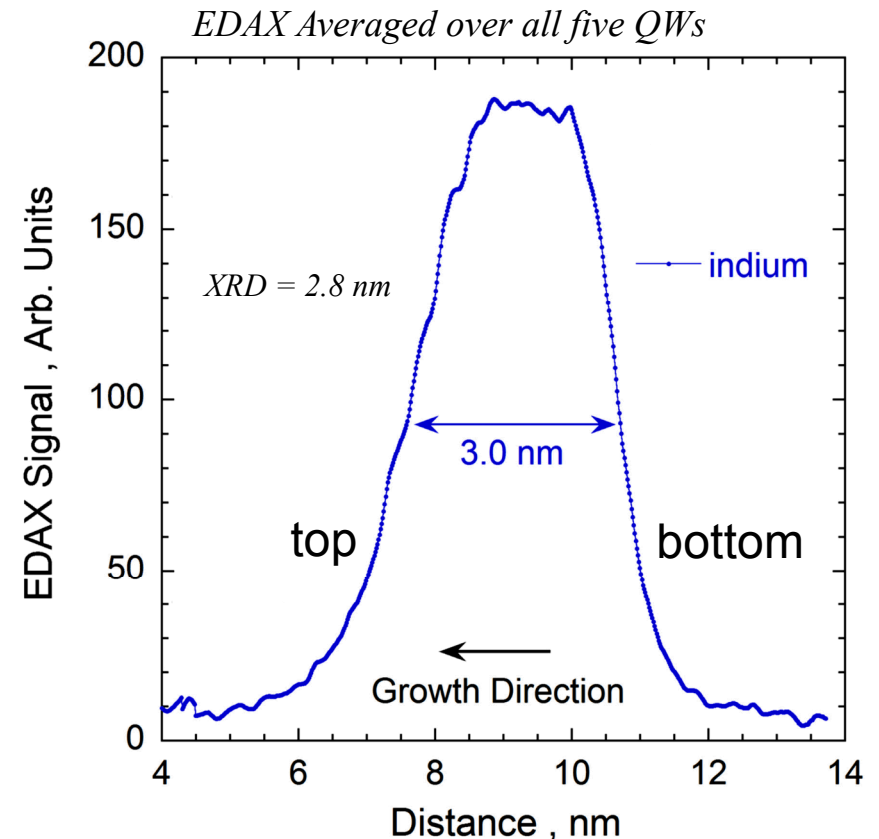
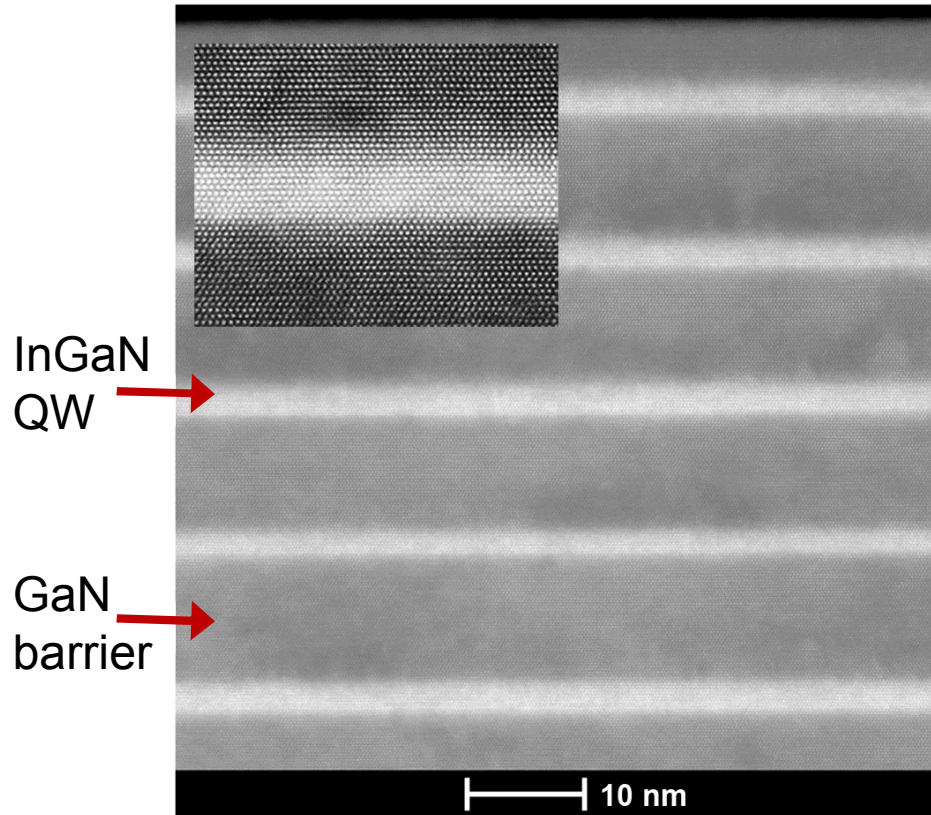
Verified with XRD that QW has 23.5 % indium





# STEM and EDAX for MQW without IL

QW at 730 °C, grow GaN barrier at 730 °C for 1 nm, continue GaN barrier growth while heating to 800 °C.

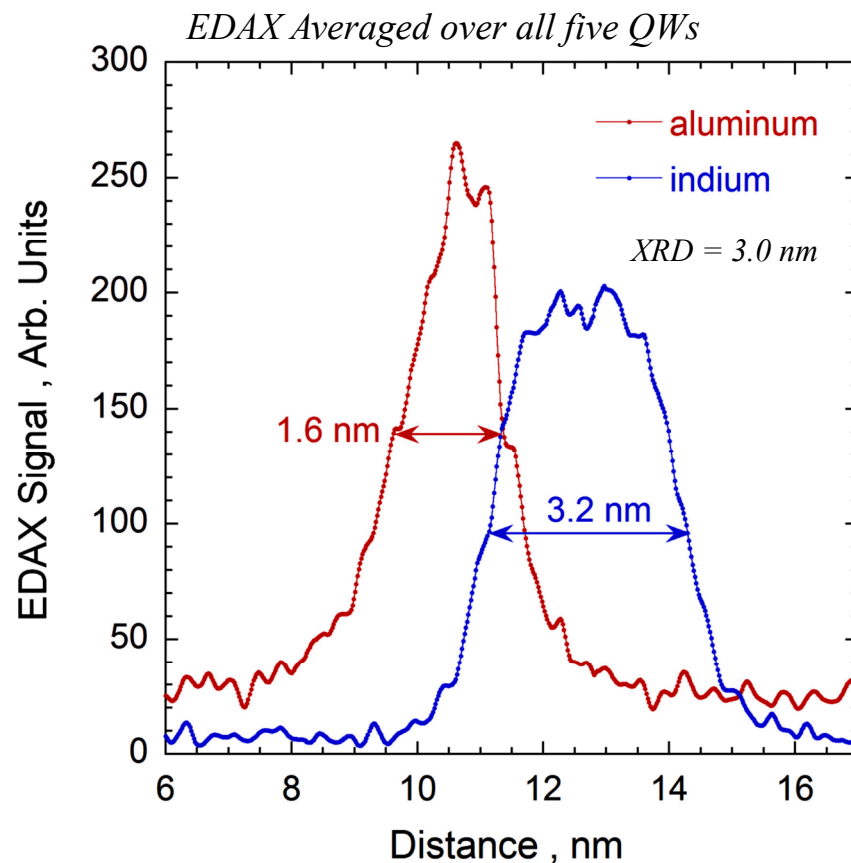
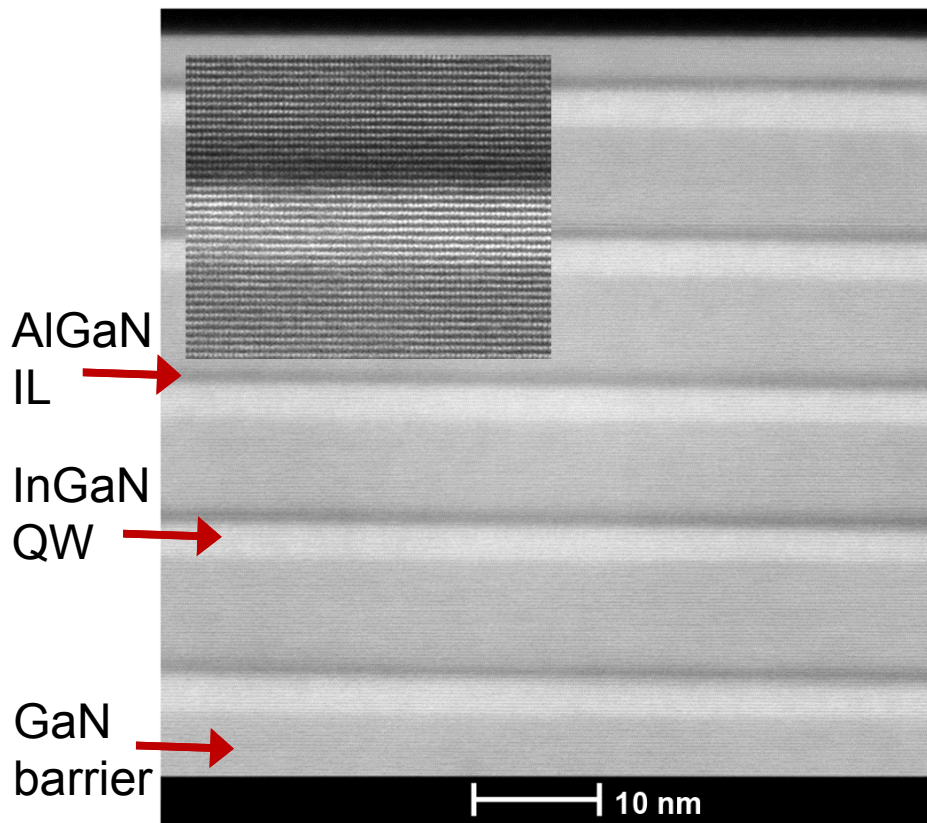


Top interface 0.5 nm thicker than bottom interface.

Reason that top interface is thicker, 1) surface indium depletion into GaN barrier or 2) indium diffusion through GaN cap during heating. 3). Can't rule out steps.

# STEM and EDAX for MQW with IL

Cap QW with IL at 700 °C, heat to 850 °C with no MOs flowing, then grow GaN barrier.

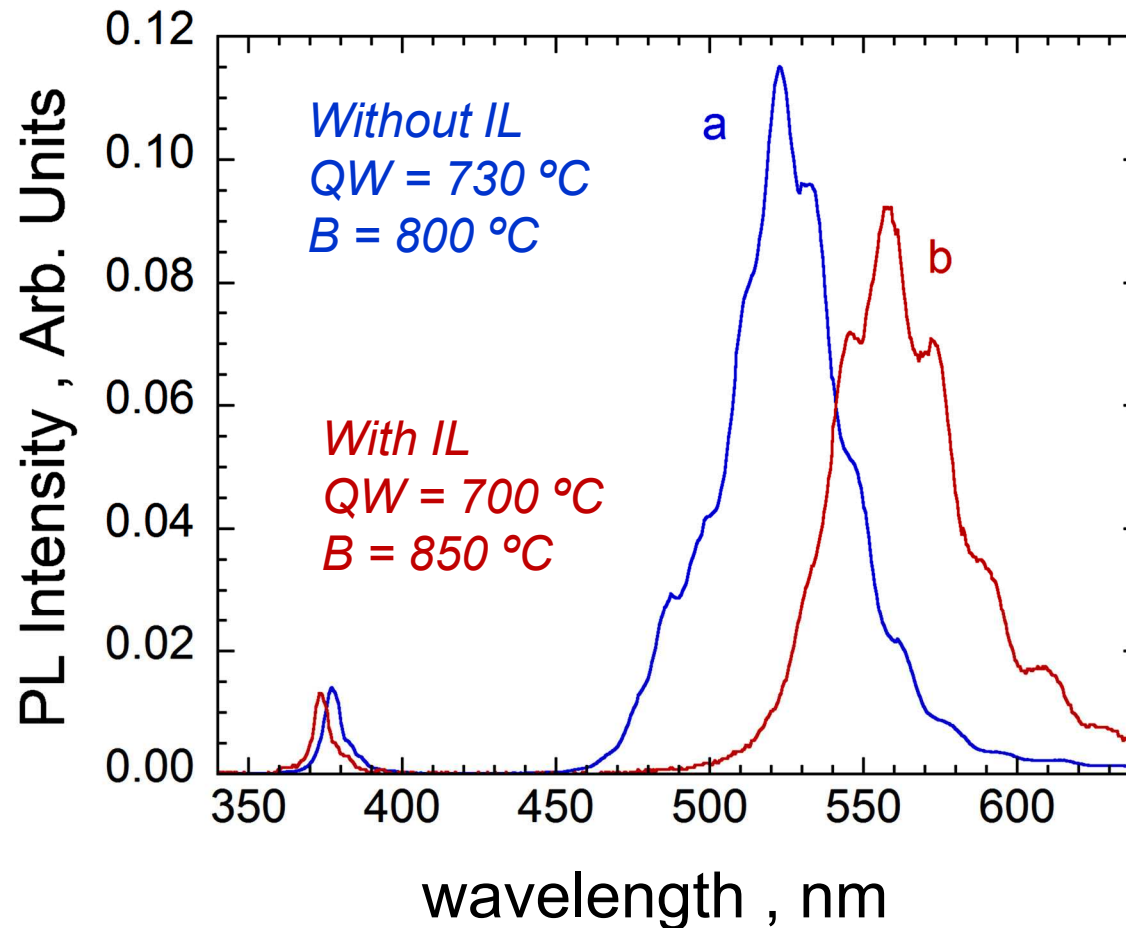


Top and bottom InGaN interfaces are both ~ 1 nm thick.

Similar InGaN interface width gives the higher order satellite peaks in the XRD.  
(see S.R. Lee, JCG 355 (2012) 63-72 for more details).



# Shift in PL wavelength using the AlGaIn IL

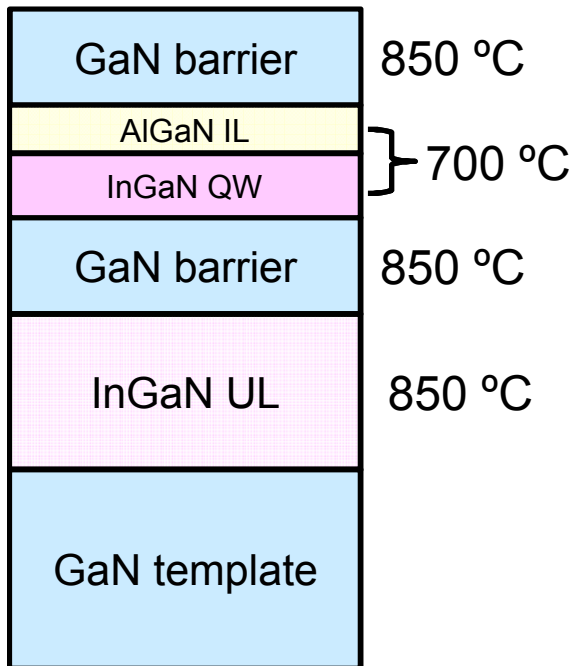


Similar PL intensity with higher indium concentration using the IL.  
How do the growth steps influence the XRD structure and PL intensity?

# Single QW with IL cap - study

## SQW structure

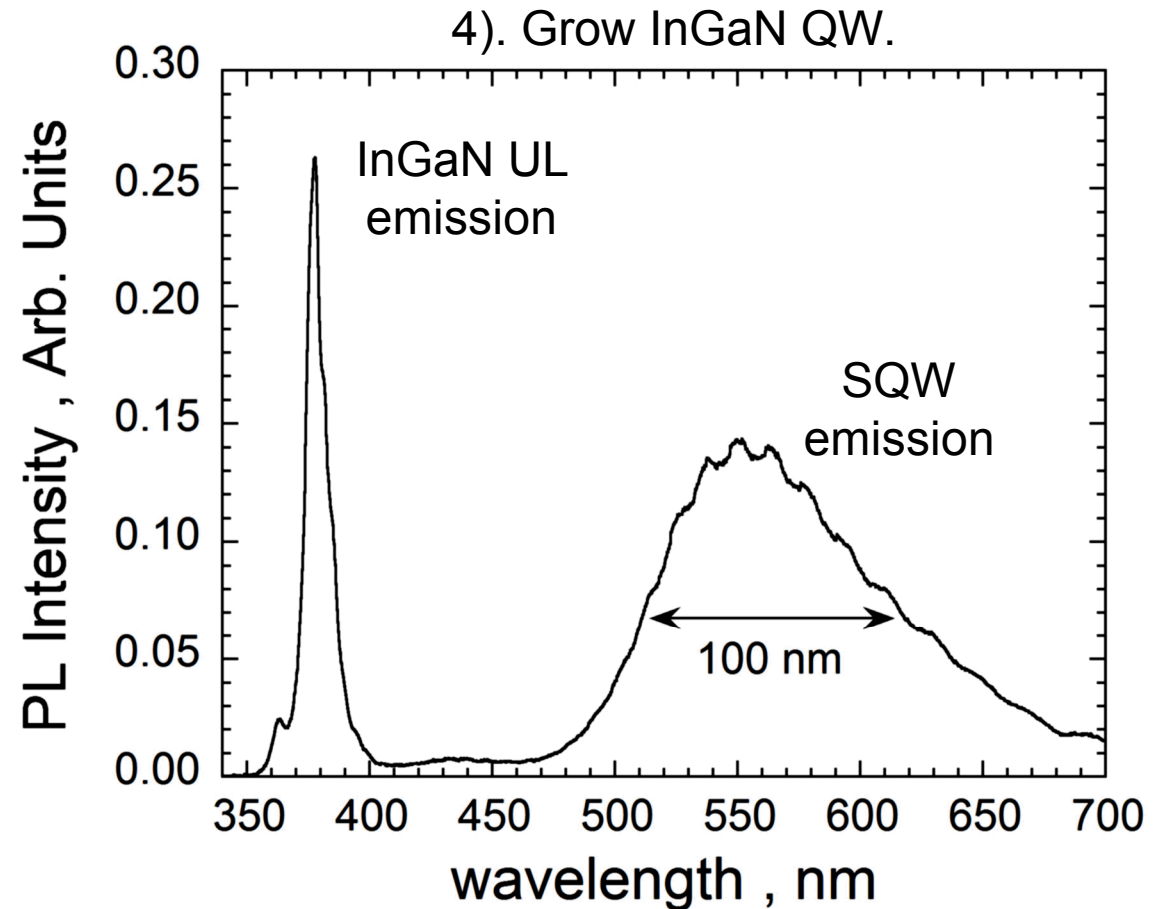
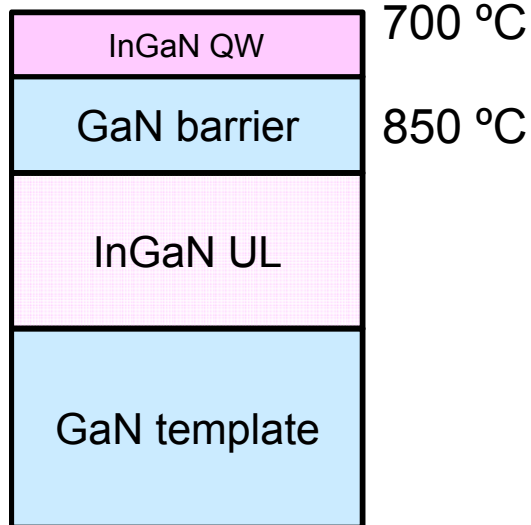
## Growth steps



- 1). InGaN UL growth at 850 °C
- 2). GaN barrier layer at 850 °C
- 3). Lower to 700 °C – stabilize
- 4). Grow InGaN QW (3.0 nm, 0.5 min.)
- 5). Grow AlGaN IL (1.5 nm, 0.3 min.)
- 6). MOs off, ramp to 850 °C (1.5 min.)
- 7). TMGa on for GaN barrier (5-6 min.)

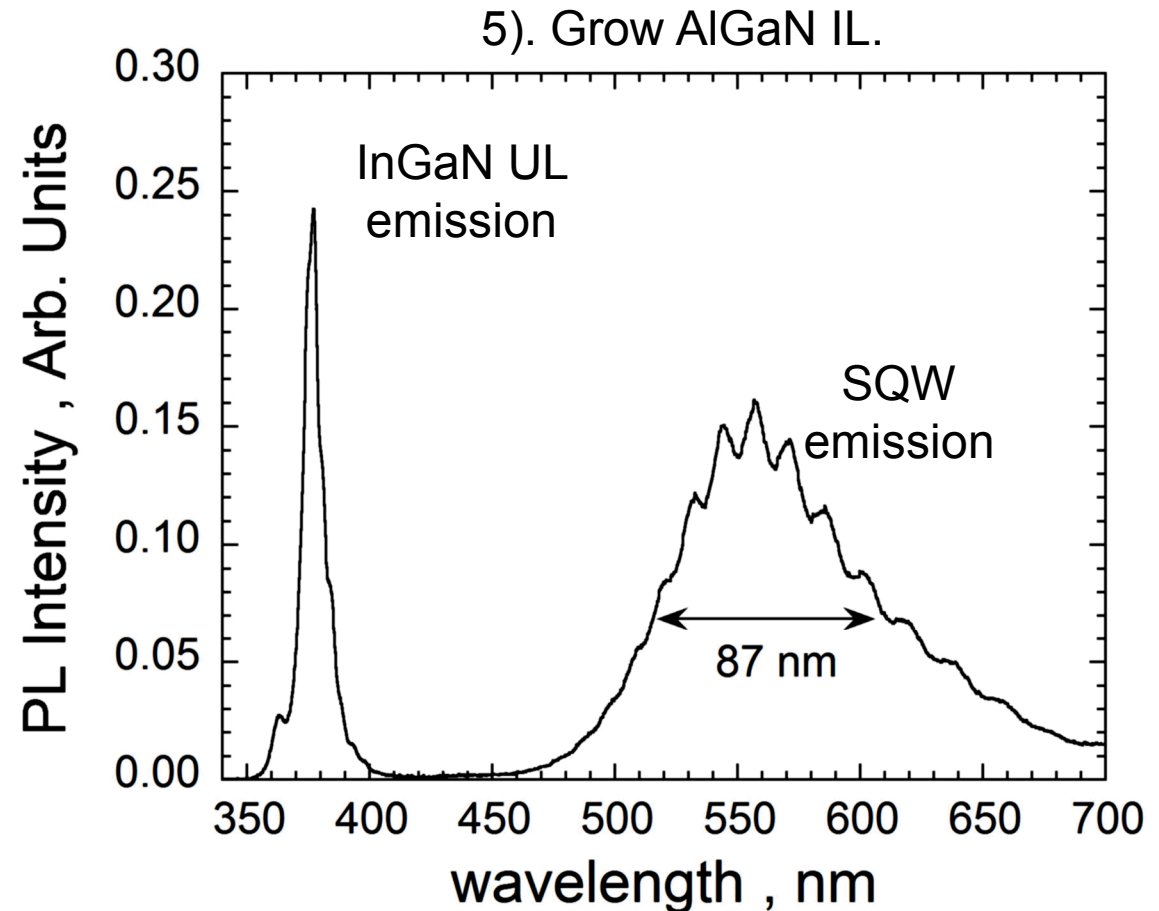
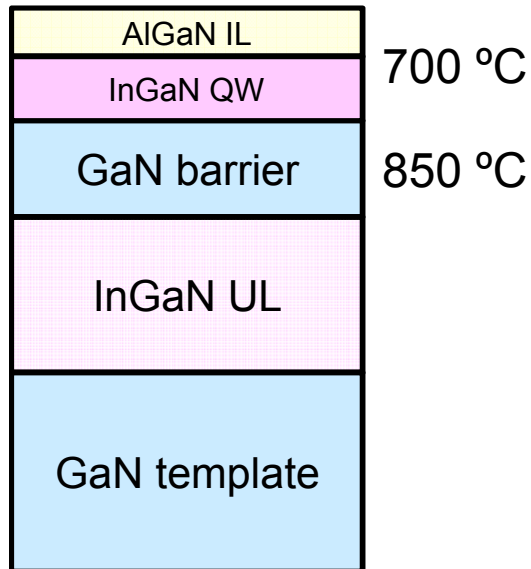
In separate growths, stop sequence after steps 4), 5), 6), and 7).

# Single QW annealing study



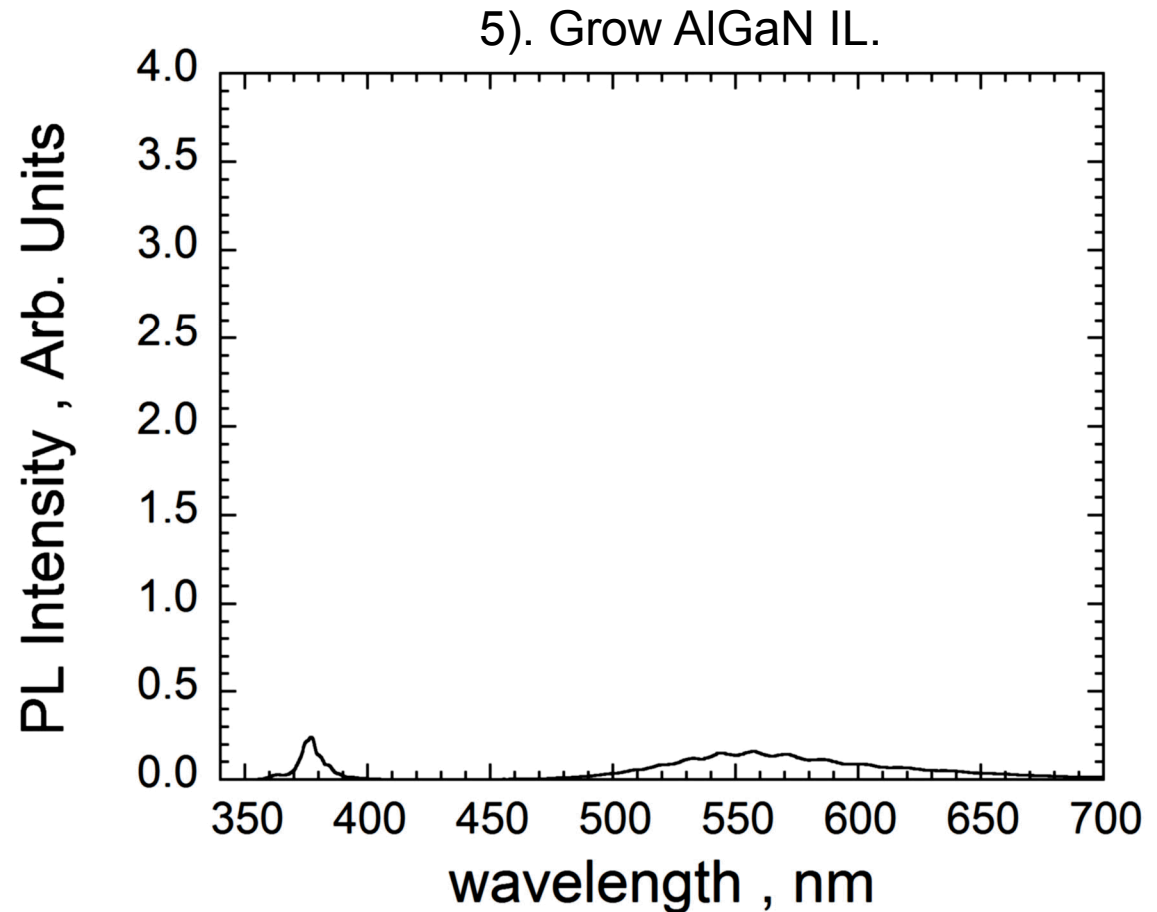
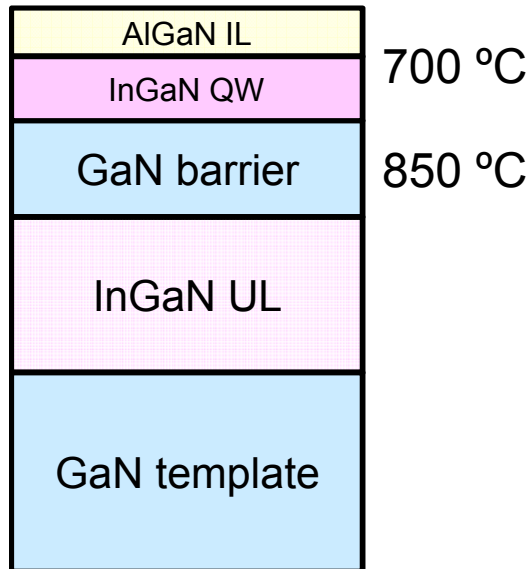
PL emission intensity broad – looks like yellow band

# Single QW annealing study



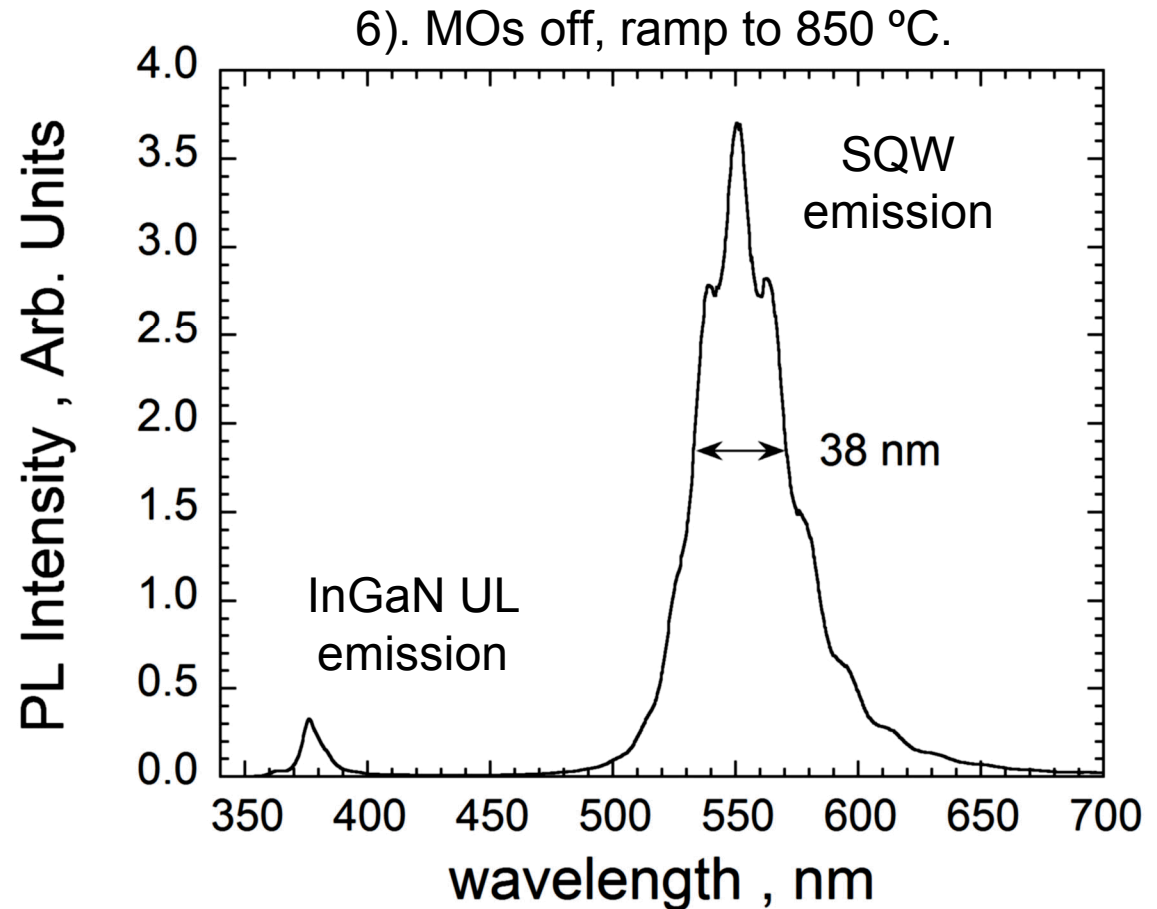
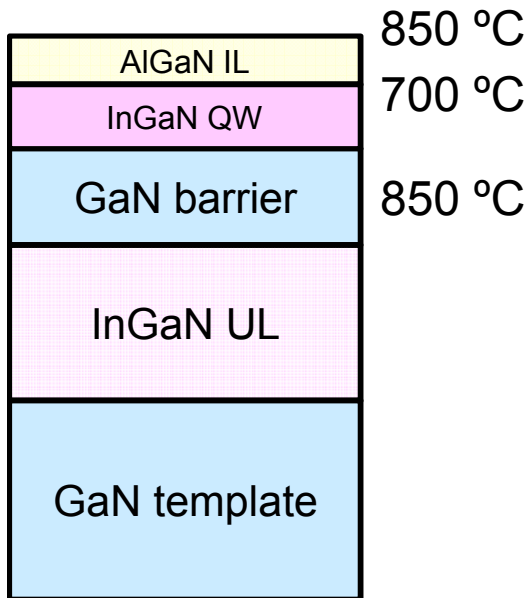
After AlGaIn IL cap layer PL emission looks similar

# Single QW annealing study



Change PL intensity scale to match next slide

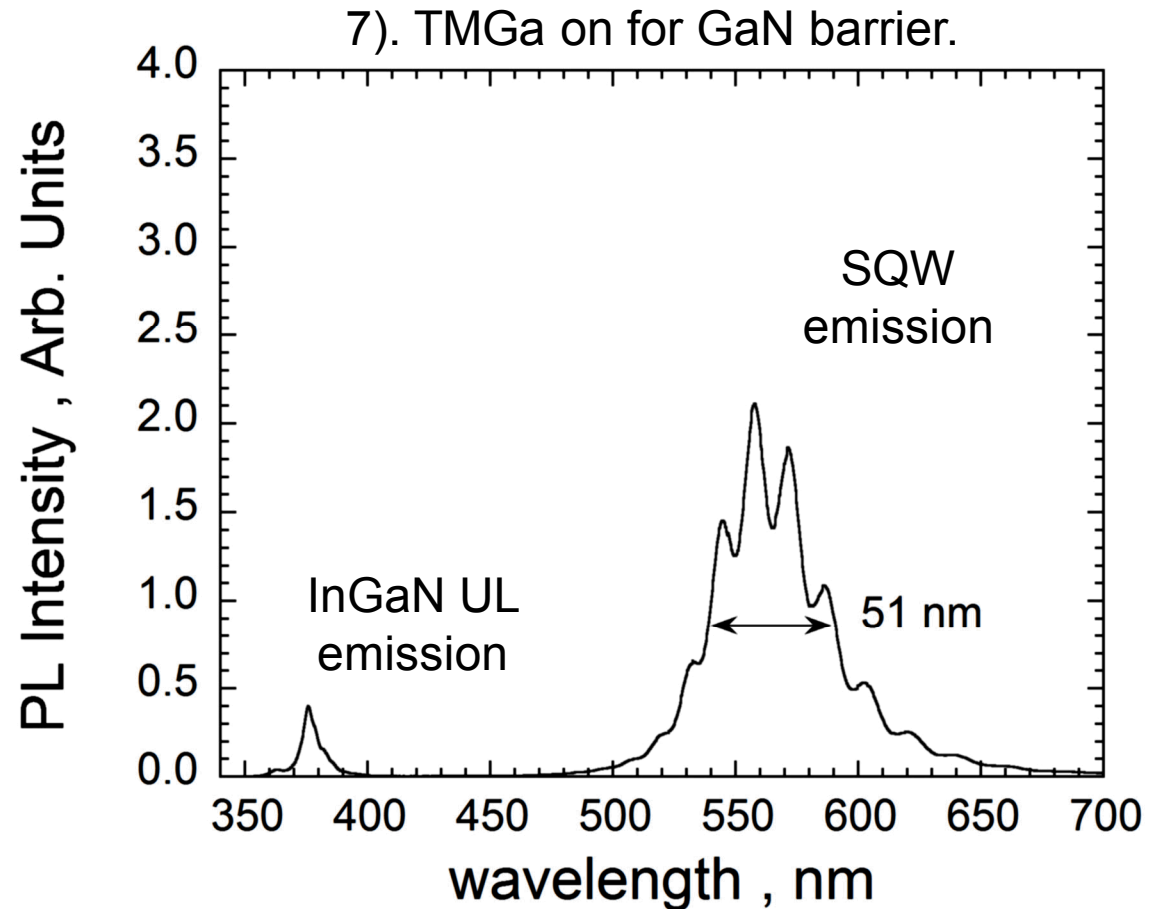
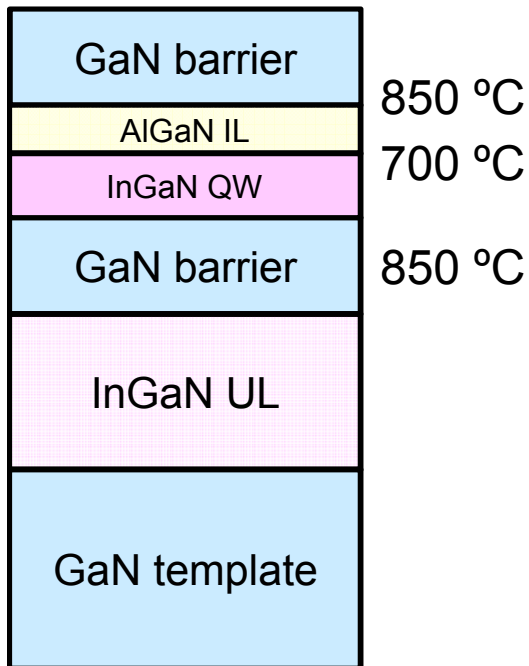
# Single QW annealing study



Annealing the AlGaIn IL capped QW improves intensity ~25x



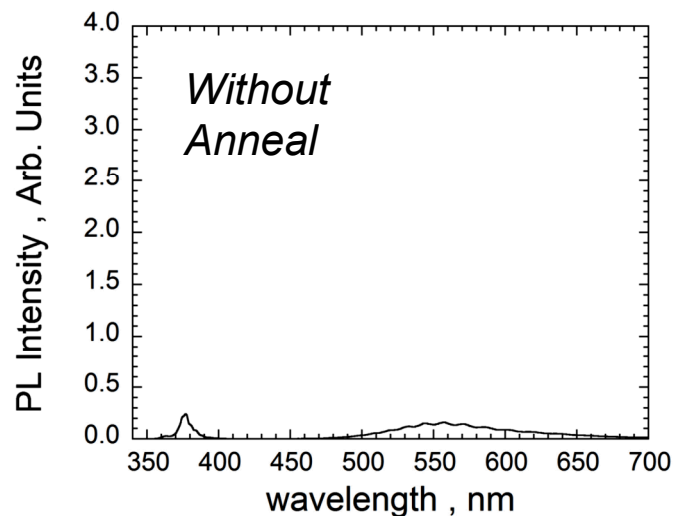
# Single QW annealing study



After the GaN barrier, decrease in intensity and slight redshift

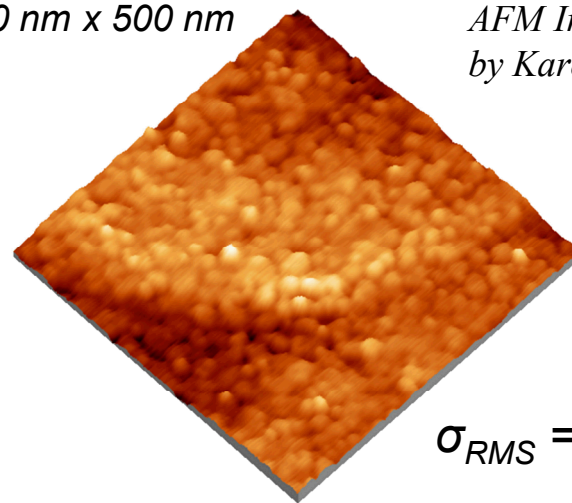
# Change in AlGaN IL surface after annealing

5). Grow AlGaN IL.



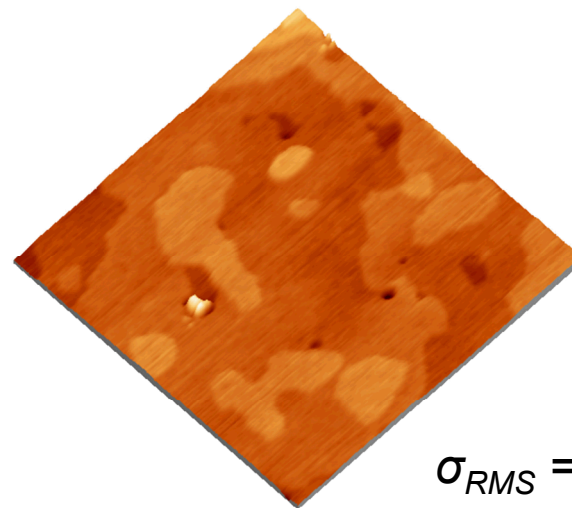
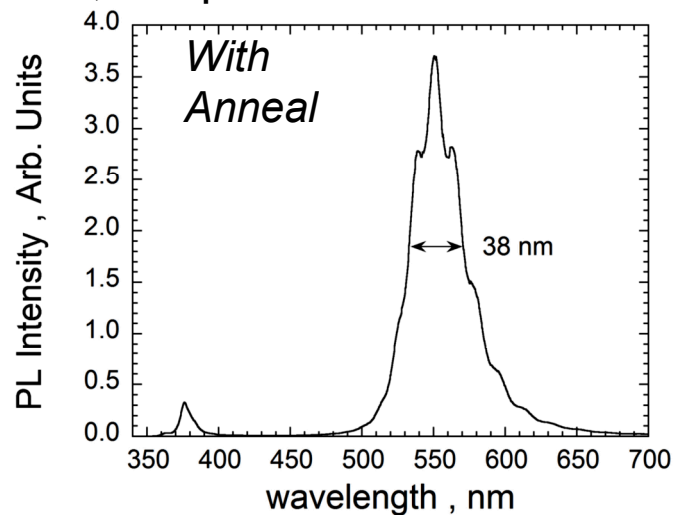
500 nm x 500 nm

*AFM Images measured  
by Karen Cross at SNL*



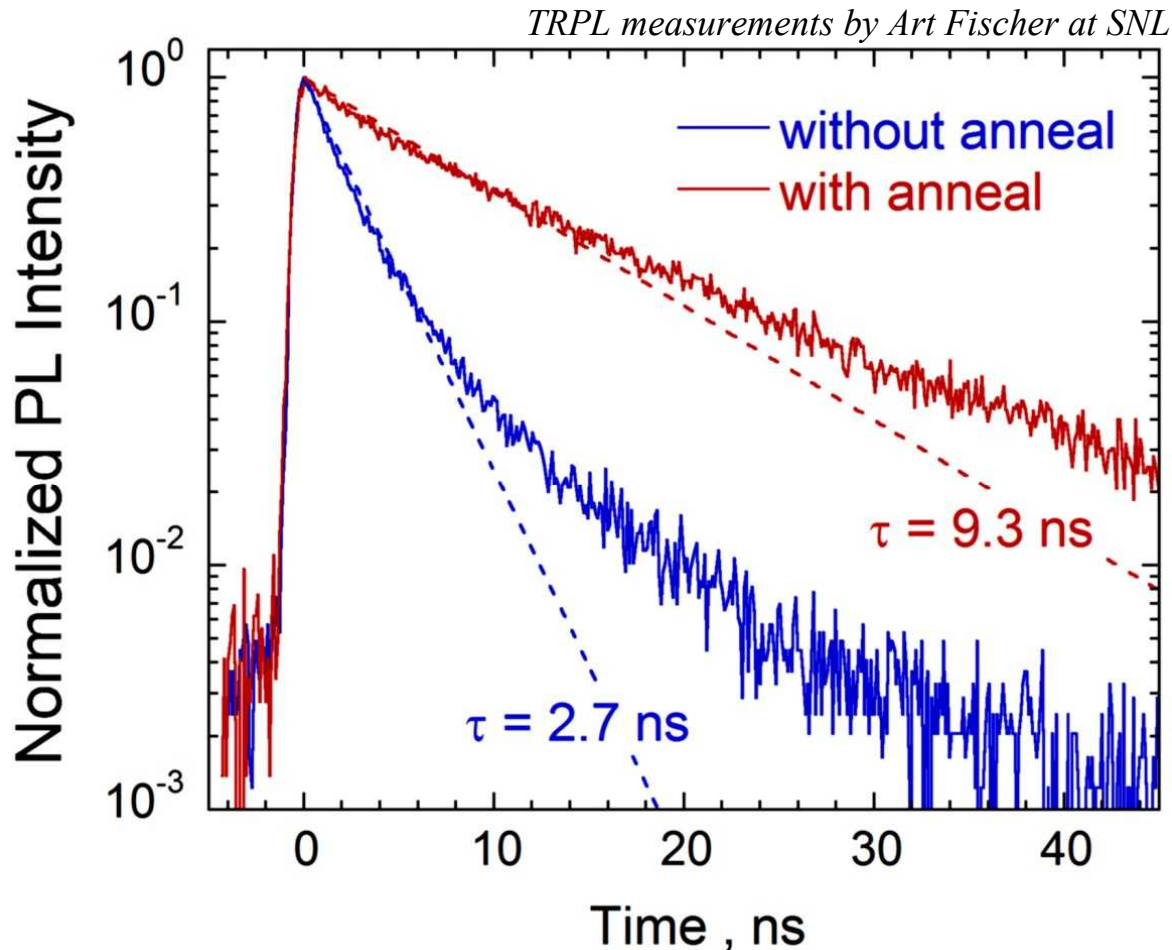
$$\sigma_{RMS} = 0.48 \text{ nm}$$

6). MOs off, ramp to 850 °C.



$$\sigma_{RMS} = 0.18 \text{ nm}$$

# Time Resolved PL with/without annealing



Annealed AlGaIn/InGaIn layer has longer lifetime than without anneal.  
Suggests decrease in non-radiative recombination centers.

# Summary of AlGa<sub>N</sub> interlayer (IL) work

- What are the exact growth conditions?
  - AlGa<sub>N</sub> IL growth? – Use InGa<sub>N</sub> QW temperature and flows. In off, Al on!
  - Use Ga<sub>N</sub> barriers. Optimal temperature is between 850 to 875 °C.
  - Growth sequence? Cap QW with IL, no MO's, ramp, then Ga<sub>N</sub> barrier.
  - Can the structures be verified using XRD? Yes – leave out indium in QWs.
- Influence of AlGa<sub>N</sub> IL on InGa<sub>N</sub> QWs.
  - Can more indium be put in the InGa<sub>N</sub> QW? – Yes, can get  $\lambda$  to 590 nm.
    - Is it possible to go above the ~20% coherency strain limit for InGa<sub>N</sub> on Ga<sub>N</sub>? Yes
    - Does the InGa<sub>N</sub> QW strain relax? No.
    - Does AlGa<sub>N</sub> IL prevent InGa<sub>N</sub> QW decomposition? Yes, better than Ga<sub>N</sub> layers.
- AlGa<sub>N</sub> IL also influences the polarization fields
  - PL wavelength? – red shift, and PL intensity? – increases after annealing.
    - If AlGa<sub>N</sub> is too thick PL intensity decreases (modeled in paper).

*More in D.D. Koleske et al., Journal of Crystal Growth 415 (2015) 57-64*

# Thanks to

- Jeff Kempisty – MOCVD growth (sorry OMVPE growth)
- Jeff Figiel – OMVPE (just doesn't sound right) growth assistance.
- Karen Cross – AFM images extraordinaire
- Paul Katula – XTEM images and EDAX profiles.
- Mike Coltrin and Jeff Tsao – Feedback on JCG manuscript.



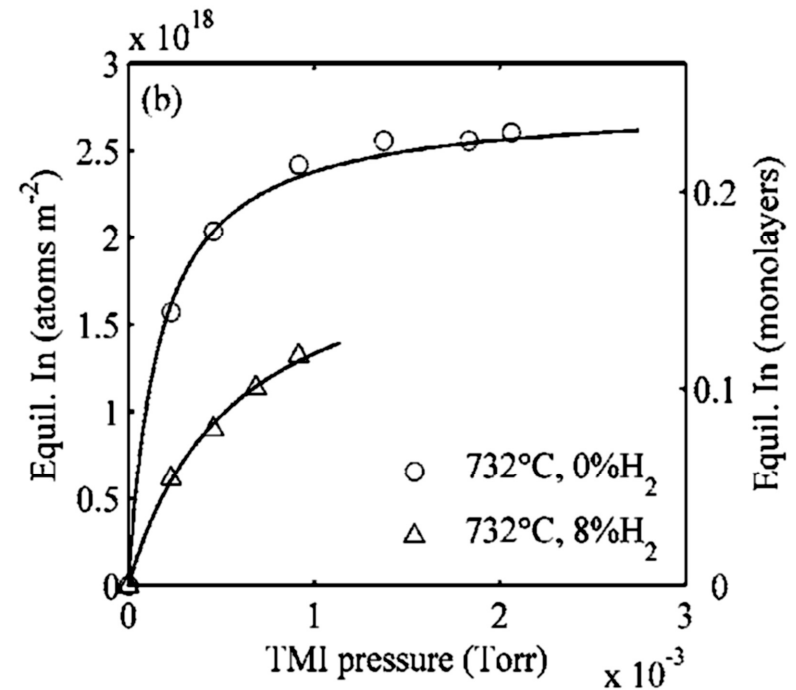
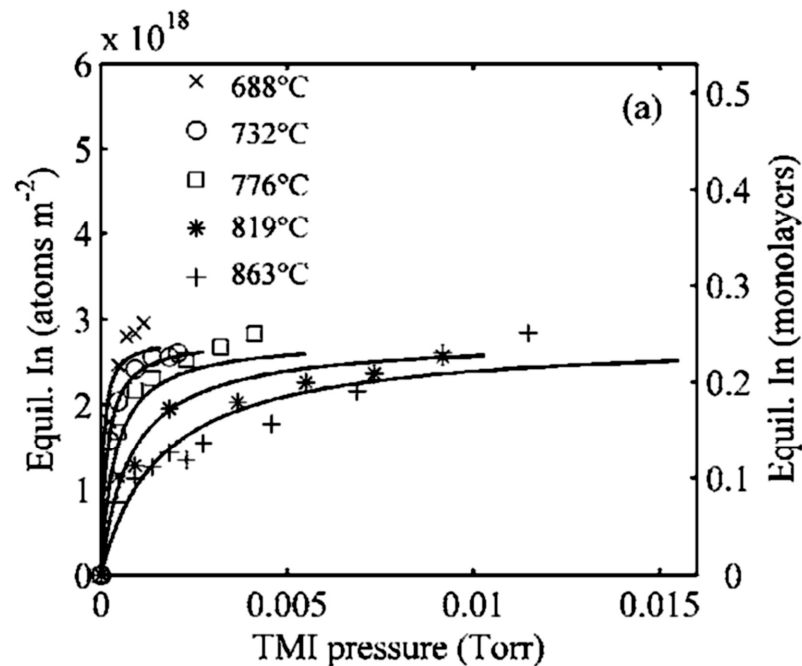
# Extra Slides



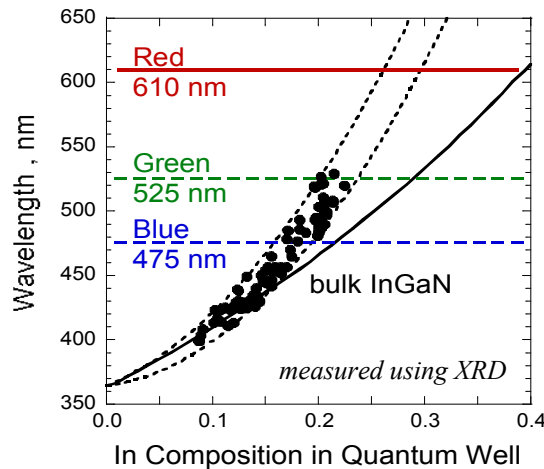
# Indium coverage up to 0.25 ML

Jiang - APL 89, 161915 (2006).

Indium adsorption on GaN under metal-organic chemical vapor deposition conditions



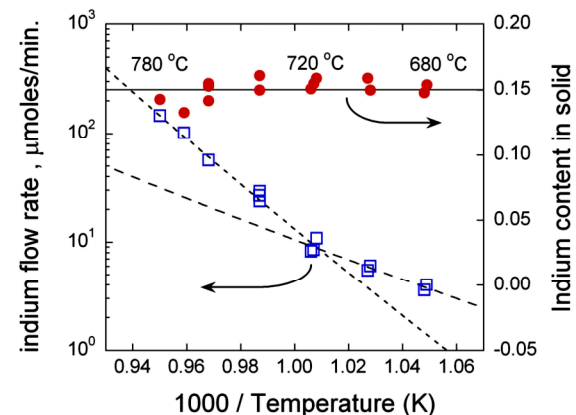
# Motivation and Issues



- Green to Red  $\lambda$  LEDs have low intensity
    - Need  $\sim 20\%$  indium for green,  $\sim 26-30\%$  red.
    - Lower temperatures required to incorporate more indium. More defects (point & impurity).
    - Increased strain on QW.
- Beneficial for red-shifting the wavelength - QCSE.  
Detrimental for e/h overlap.

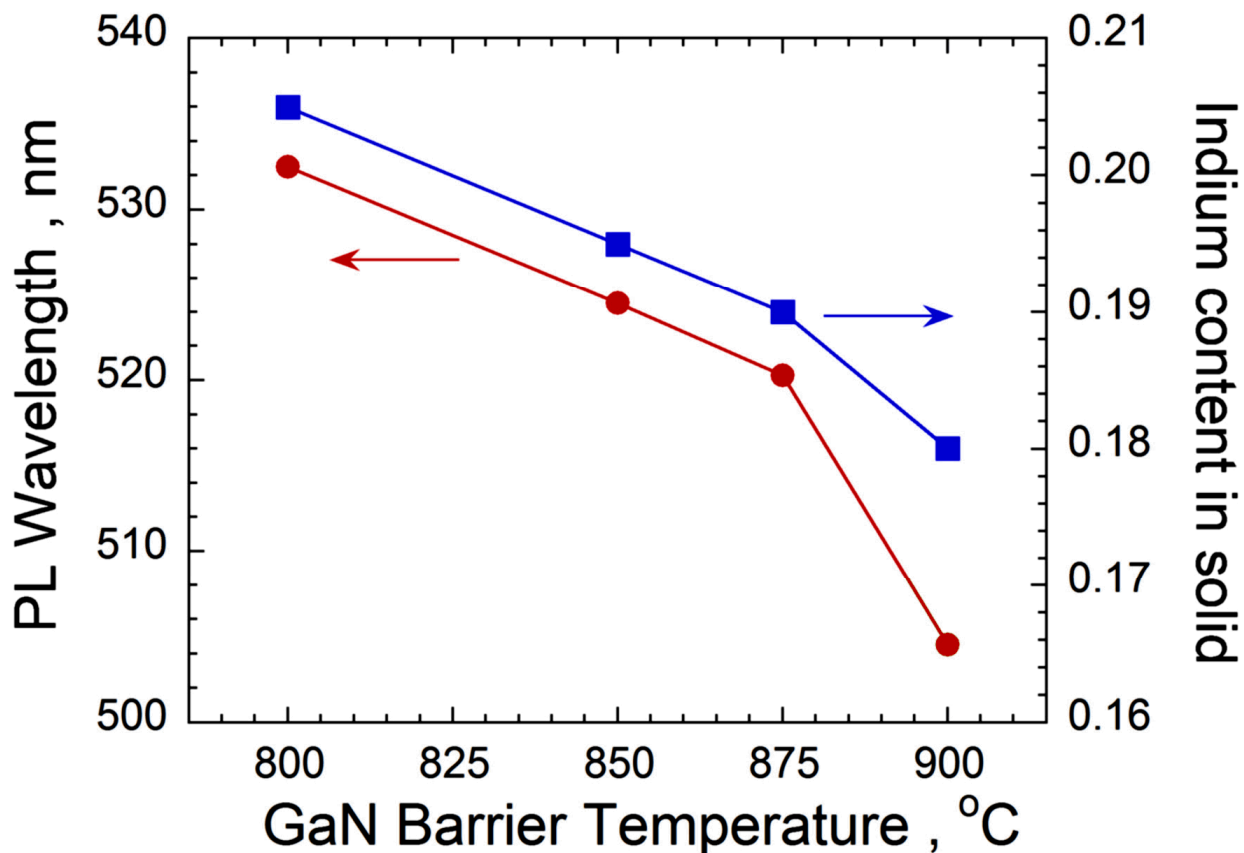
## ■ InGaN growth issues

- Indium reservoir on the surface.  
Takes time build up and deplete.  
Hard to produce abrupt interfaces.
- Like to grow InGaN QWs as hot as possible, however need exponentially more indium to reach same indium %.



# Influence of GaN barrier temperature

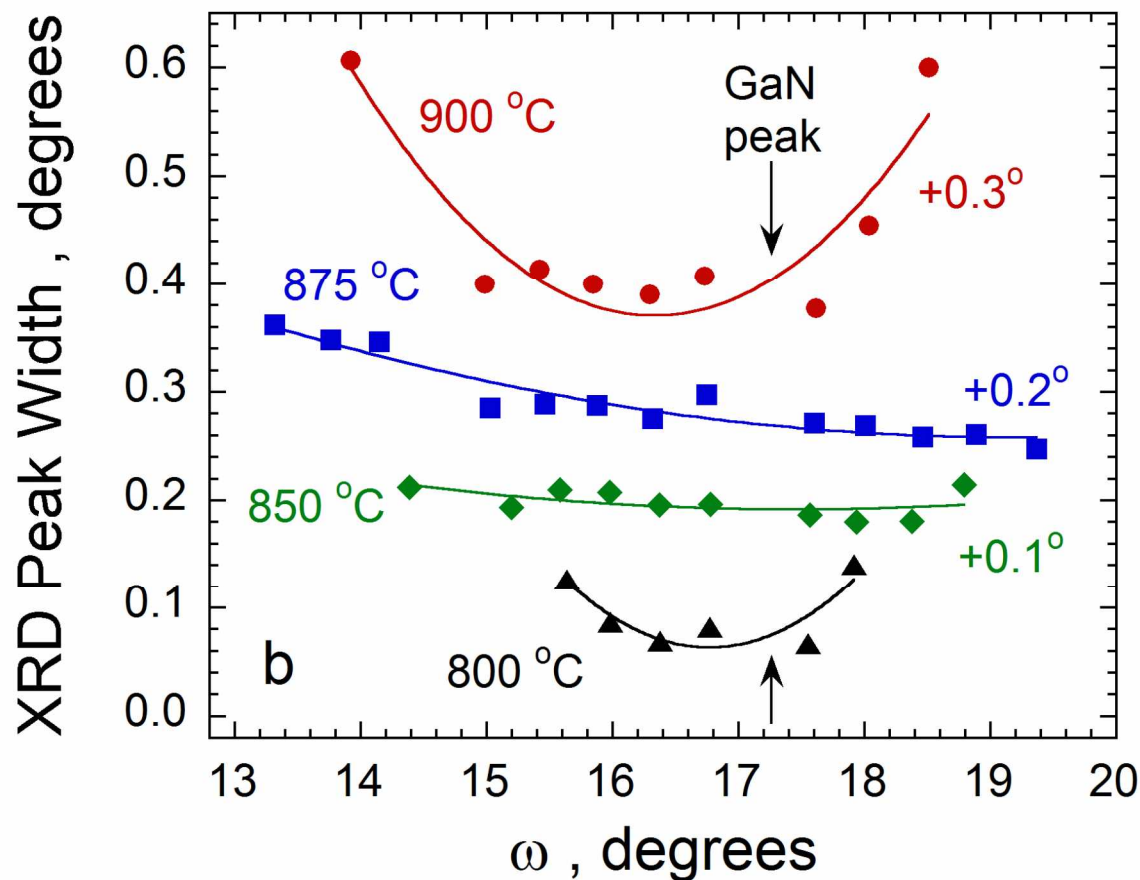
QW at 710 °C, AlGaIn at 710 °C, temperature ramp, GaN barrier growth



During the anneal some indium from QW escapes through the AlGaIn cap layer.  
More indium would escape if GaN barriers were used.

# Influence of GaN barrier temperature

XRD satellite peakwidth as a function of angle

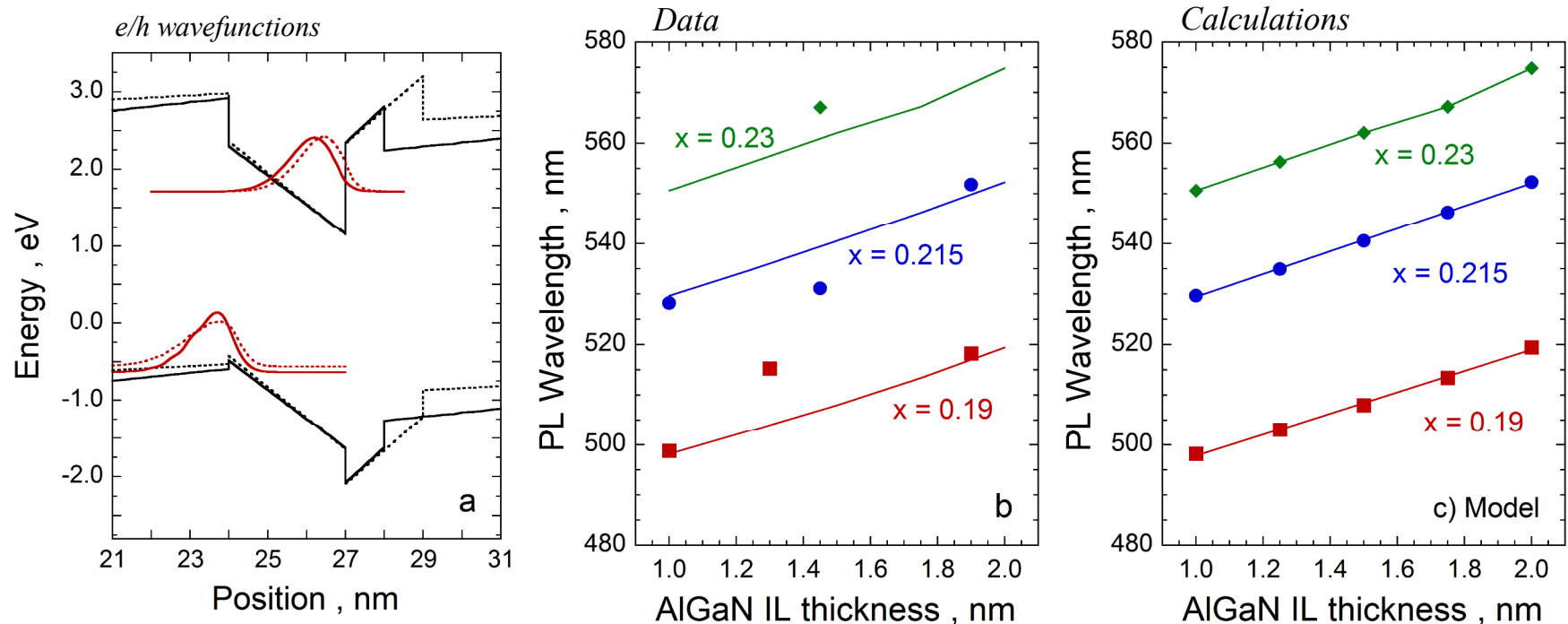


Consistent  
with the  
TEM, GaN  
barriers at  
850 °C

Smoothest interfaces for GaN barriers grown at 850 and 875 °C

# Wavelength shift vs. AlGaN IL thickness

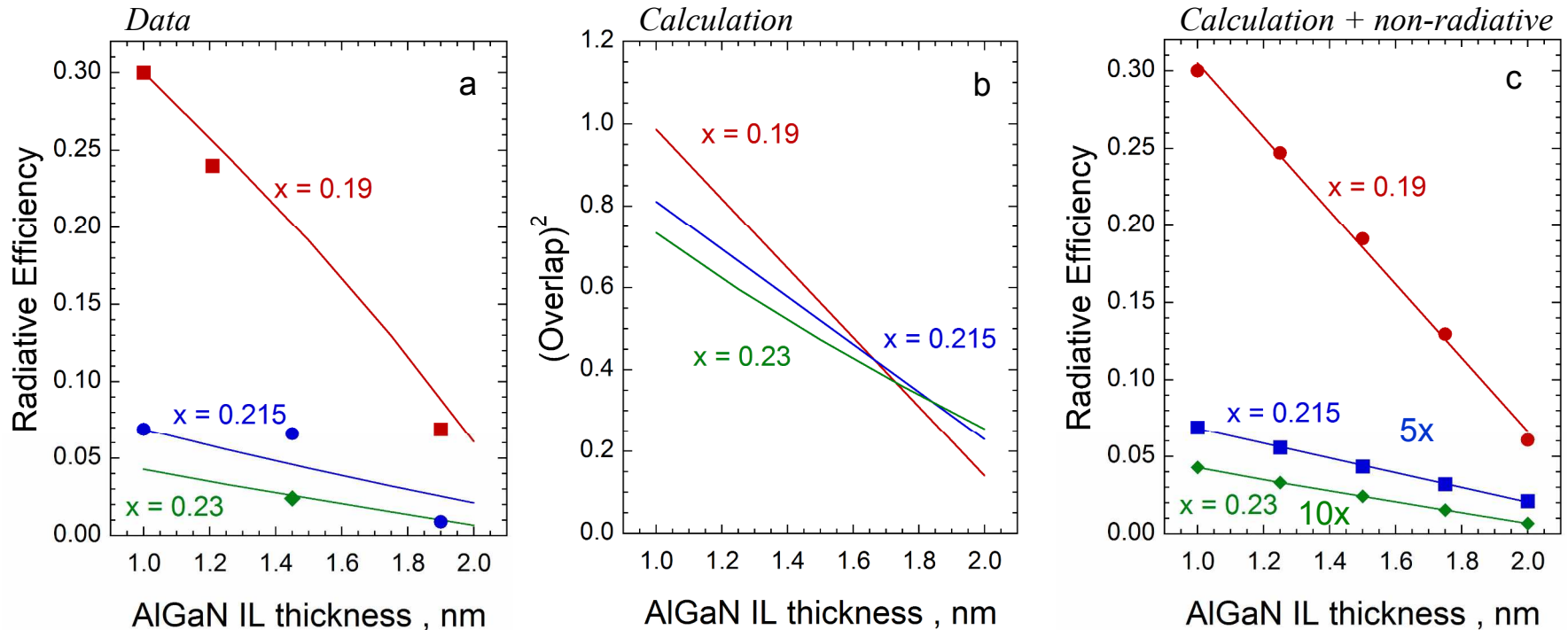
NEXTNANO3 ([www.nextnano.de](http://www.nextnano.de)) calculations by Jon Wierer.



- Used 40 % AlGaN IL, 3 nm QW with  $\text{In}_x\text{Ga}_{1-x}\text{N}$ , and 10 nm GaN barriers
- Increasing AlGaN IL thickness – brings e/h wavefunctions closer, but decreases overlap.
- QWs grown at 700 ( $x = 0.23$ ), 710 ( $x = 0.215$ ), and 730 °C ( $x = 0.19$ ), barrier at 800 °C.

**PL wavelengths increases as the AlGaN IL thickness increases**

# PL Intensity vs. AlGaN IL thickness



- Experimental radiative efficiency decreases as the AlGaN IL thickness increases.
- Wavefunction overlap squared decreases as the AlGaN IL thickness increases.
- Adding non-radiative component (SRH) as indium ( $x$ ) increases gives better data match.

Annealing QW gets rid of some of the non-radiative centers, but not all.